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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
(19,910,824	07/24/2001	Hiroshi Tobimatsu	50090-306	3928

7590

08/02/2002

McDermott, Will & Emery 600 13th Street, N.W. Washington, DC 20005-3096

EXAMINER LEE, HSIEN MING

ART UNIT PAPER NUMBER

2823

DATE MAILED: 08/02/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

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-		Application	No.	TOBIMATSU ET AL.	
	Office Action Summer	09/910,824			
•	Office Action Summary	Examiner		Art Unit	
		Hsien-Ming		2823	
Period fo	The MAILING DATE of this communication or Reply	appears on the co	over sheet with the o	correspondence add	dress
THE - Exte after - If the - If NO - Failu - Any	ORTENED STATUTORY PERIOD FOR REIMALING DATE OF THIS COMMUNICATION in many be available under the provisions of 37 CFR SIX (6) MONTHS from the mailing date of this communication, a period for reply specified above is less than thirty (30) days, a period for reply is specified above, the maximum statutory per interest or reply within the set or extended period for reply will, by state reply received by the Office later than three months after the material patent term adjustment. See 37 CFR 1.704(b).	N. 8.1.136(a). In no event, reply within the statutory iod will apply and will ex- atute, cause the application.	nowever, may a reply be tir minimum of thirty (30) day pire SIX (6) MONTHS from on to become ABANDONE	mely filed /s will be considered timely the mailing date of this co	mmunication.
1)	Responsive to communication(s) filed on				
2a)		This action is no	n-final.		
3) <u></u> Dispositi	Since this application is in condition for allo closed in accordance with the practice und ion of Claims	owance except fo ler <i>Ex parte Qua</i> y	r formal matters, pi de, 1935 C.D. 11, 4	rosecution as to the 453 O.G. 213.	e merits is
4)⊠	Claim(s) 1-6 is/are pending in the application	on.			
	4a) Of the above claim(s) is/are withd	frawn from consid	deration.		
5)	Claim(s) is/are allowed.				
6)[]	Claim(s) <u>1-6</u> is/are rejected.				
7)	Claim(s) is/are objected to.				
8)	Claim(s) are subject to restriction and	d/or election requ	irement.		
Applicati	on Papers				
9) 🗌 -	The specification is objected to by the Exami	iner.			
10) 🔲 ื	The drawing(s) filed on is/are: a)□ ac	cepted or b) obj	ected to by the Exa	miner.	
	Applicant may not request that any objection to				
11) 🔲 -	The proposed drawing correction filed on	is: a) 🗌 appro	oved b) disappro	ved by the Examine	r.
	If approved, corrected drawings are required in	• /	action.		
	The oath or declaration is objected to by the	Examiner.			
riority u	nder 35 U.S.C. §§ 119 and 120				
13)[[Acknowledgment is made of a claim for fore	ign priority under	35 U.S.C. § 119(a)-(d) or (f).	
a)[☑ All b) ☐ Some * c) ☐ None of:				
	1. Certified copies of the priority docume	ents have been re	ceived.		
	2. Certified copies of the priority docume	ents have been re	ceived in Application	on No	
	3. Copies of the certified copies of the prapplication from the International Eee the attached detailed Office action for a li	Bureau (PCT Rul	e 17.2(a)).		itage
	cknowledgment is made of a claim for dome				application)
	☐ The translation of the foreign language p				1-E
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ttachment	(s)				
) 🔲 Notice	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449) Paper No(s)	4) [5) [6) [(PTO-413) Paper No(s Patent Application (PTO-	
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- 020 (116)	Office	Action Summary		Part of I	Paper No. 4

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DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-6 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shinohara (US 6,127,099) in view of Sakurai (US 6,287,750) and Fu et al. (US 5,807,787).

Regarding claims 1-4 and 6. Shinohara teaches the claimed method of manufacturing a semiconductor device (Figs. 2Λ -2G and related text) comprising the steps of :

- forming an interconnection 14 on a semiconductor substrate 11/12 having a semiconductor element such as a wiring element (not shown) formed thereon;
- forming a passivation film 15 (Si3N4) on the semiconductor substrate 11/12 including the interconnection 14 (Fig.2C);
- forming a photosensitive polyimide film 16 by spin-on-coating a polyimide precursor (col.3, lines 9-10), which is served as a buffer coating film, on the passivation film15 (Fig.2D);
- patterning the photosensitive polyimide film 16 (Fig. 2E);
- etching the passivation film 15 while the patterned photosensitive polyimide film 16 is taken as a mask ,i.e. forming the opening (Fig.2F);

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• ashing the surface of the substrate 11/12 by an oxygen plasma, inherently including ashing the surface of the polyimide film 16, as a result of the etching (col. 3, lines 20-44); and

• curing the semiconductor substrate 11/12 by subjecting the substrate 11/12 to a heat treatment at a temperature of between 300 C and 400 C for a time of 60 minutes to 120 minutes to transform the polyimide film 16 into imide (col.3, lines 23-25).

Shinohara does not expressly teach that the ashing step is to remove a hardened layer formed on the surface of the photosensitive polyimide film 16 as a result of the etching. However, it would have been obvious to one artisan at the time of the invention was made to appreciate that the ashing step of Shinohara would inherently remove any undesirable residual layer such as the claimed hardened layer formed on the surface of the photosensitive polyimide film 16 because Shinohara teaches the ashing process using oxygen plasma for the removing, which is the same technique as claimed for removing the hardened layer. In other words, the removing of the hardened layer is the consequence of the ashing process of Shinohara even though he is silent as to the hardened layer. This can be substantiated by the ashing process of Sakurai, in which he teaches utilizing the ashing process by the oxygen plasma to remove a hardened layer from the surface of a photoresist layer 205 (col.2, lines 41-49, Sakurai), in which the photoresist layer can be the photosensitive polyimide film, which is further evidenced by Fu et al. (col. 5, lines 39-40).

Regarding claim 5, the selection of the removed thickness is obvious because it is a matter of determining optimum process condition by routine experimentation with a

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limited number of species. In re Jones, 162 USPQ 224 (CCPA 1955)(the selection of optimum ranges within prior art general conditions is obvious) and In re Boesch, 205 USPQ 215 (CCPA 1980)(discovery of optimum value of result effective variable in a known process is obvious). In this case, it would have been obvious to one artisan in the art to remove a desired thickness from the polyimide film during the ashing process as taught by Shinohara in view of Sakurai to eliminate the hardened layer formed on the surface of the polyimide film without compromising the integrity of the remaining thickness of the polyimide film. In such a situation, the applicant must show that the particular range is critical, generally by showing that the claimed range achieves unexpected results. See M.P.E.P. 2144.05 III.

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hsien-Ming Lee whose telephone number is 703-305-7341. The examiner can normally be reached on M-F (9:00 \sim 5:00).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor. Wael Fahmy can be reached on 703-308-4918. The fax phone numbers for the organization where this application or proceeding is assigned are 703-305-0142 for regular communications and 703-305-0142 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

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Hsien Ming Lee July 31, 2002

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